Supertex inc.



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

BV _{DSS} /	R _{DS(ON)}	I _{D(ON)}	Order Number / Package		
BV _{DGS}	(max)	(min)	TO-92		
60V	7.5Ω	500mA	2N7008		

Features

- ☐ Free from secondary breakdown
- □ Low power drive requirement
- □ Ease of paralleling
- □ Low C_{ISS} and fast switching speeds
- Excellent thermal stability
- Integral Source-Drain diode
- High input impedance and high gain
- ☐ Complementary N- and P-channel devices

Applications

Motor	controls
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□ Converters

☐ Amplifiers

☐ Switches

Power supply circuits

 Drivers (relays, hammers, solenoids, lamps, memories, displays, bipolar transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_DSS
Drain-to-Gate Voltage	BV _{DGS}
Gate-to-Source Voltage	± 30V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

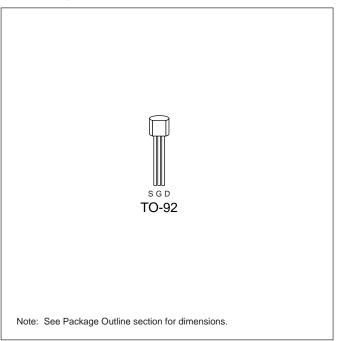
^{*} Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex's vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options



Thermal Characteristics

Package	I _D (continuous)*	I _D (pulsed)	Power Dissipation @ T _C = 25°C	$ heta_{ m jc}$ $^{\circ}$ C/W	θ _{ja} °C/W	I _{DR} *	I _{DRM}
TO-92	230mA	1.3A	1W	125	170	230mA	1.3A

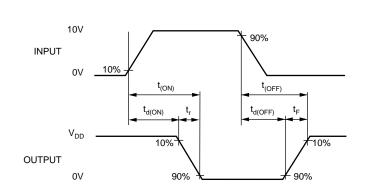
^{*} I_D (continuous) is limited by max rated T_j .

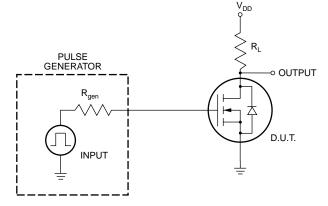
Electrical Characteristics (@ 25°C unless otherwise specified)

Symbol	Parameter	Min	Тур	Max	Unit	Conditions	
BV _{DSS}	Drain-to-Source Breakdown Voltage	60			V	$I_D = -10\mu A, V_{GS} = 0V$	
V _{GS(th)}	Gate Threshold Voltage	1		2.5	V	$V_{GS} = V_{DS}, I_D = 250\mu A$	
I _{GSS}	Gate Body Leakage			100	nA	$V_{GS} = \pm 30V, V_{DS} = 0V$	
I _{DSS}	Zero Gate Voltage Drain Current			1	μΑ	$V_{GS} = 0V$, $V_{DS} = 50V$	
				500	μΑ	$V_{GS} = 0V, V_{DS} = 50V$ $T_A = 125^{\circ}C$	
I _{D(ON)}	ON-State Drain Current	500			mA	$V_{GS} = 10V, V_{DS} \ge 2V_{DS(ON)}$	
R _{DS(ON)}	Static Drain-to-Source ON-State Resistance			7.5	0	$V_{GS} = 5V$, $I_D = 50mA$	
				7.5	Ω	V _{GS} = 10V, I _D = 500mA	
G _{FS}	Forward Transconductance	80			mΩ	$V_{DS} = 10V, I_{D} = 0.2A$	
C _{ISS}	Input Capacitance			50			
C _{oss}	Common Source Output Capacitance			25	pF	$V_{GS} = 0V$, $V_{DS} = 25V$ f = 1 MHz	
C _{RSS}	Reverse Transfer Capacitance			5			
t _(ON)	Turn-ON Time			20	20	$V_{DD} = 30V, I_{D} = 200 \text{ mA},$	
t _(OFF)	Turn-OFF Time			20	ns	$R_{GEN} = 25\Omega$	
V _{SD}	Diode Forward Voltage Drop			1.5	V	$I_{SD} = 150$ mA, $V_{GS} = 0$ V	

Notes:

Switching Waveforms and Test Circuit





^{1.} All D.C. parameters 100% tested at 25° C unless otherwise stated. (Pulse test: 300μ s pulse, 2% duty cycle.)

^{2.} All A.C. parameters sample tested.